

Failure Modes, Effects and Diagnostic Analysis

Project: 2130 Level Switch

Company: Rosemount Tank Radar Sweden

Contract Number: Q23/10-056 Report No.: ROS 20-09-098 R004 Version V4, Revision R2, March 7, 2024 Valerie Motto

Management Summary

This report summarizes the results of the hardware assessment in the form of a Failure Modes, Effects, and Diagnostic Analysis (FMEDA) of the 2130 Level Switch, as described in section [2.5.1.](#page-7-0) A Failure Modes, Effects, and Diagnostic Analysis is one of the steps to be taken to achieve functional safety certification per IEC 61508 of a device. From the FMEDA, failure rates are determined. The FMEDA that is described in this report concerns only the hardware of the 2130 Level Switch. For full functional safety certification purposes all requirements of IEC 61508 must be considered.

The 2130 Level Switch is a 2/3-wire smart device used to sense whether the process level is above or below a particular point. The 2130 Level Switch contains self-diagnostics and is programmed to send its output to a specified failure state upon internal detection of a failure.

[Table 1](#page-1-0) gives an overview of the different versions that were considered in the FMEDA of the 2130 Level Switch.

Table 1 Version Overview

The 2130 Level Switch is classified as a Type B^1 element according to IEC 61508, having a hardware fault tolerance of 0.

The failure rate data used for this analysis meets the *exida* criteria for Route 2_H (see Section [5.2\)](#page-25-0) (and the diagnostic coverage resulting from the analysis exceeds the required 60% threshold). All Models of the 2130 Level Switch can be classified as a 2_H device and meets the hardware architectural constraints up to SIL 2 at HFT=0 (or SIL 3 at HFT=1). The unit must be properly designed into a Safety Instrumented Function per the Safety Manual requirements and supported via a calculation of PFH/PFD_{avg}.

These failure rates are valid for the useful lifetime of the product, see section [4.6.](#page-24-0)

The failure rates listed in this report are based on over 400 billion unit operating hours of process industry field failure data. The failure rate predictions reflect realistic failures and include site specific failures due to human events for the specified Site Safety Index (SSI) [\[N10\],](#page-6-0) [\[N11\].](#page-6-1)

A user of the 2130 Level Switch can utilize these failure rates in a probabilistic model of a safety instrumented function (SIF) to determine suitability in part for safety instrumented system (SIS) usage in a particular safety integrity level (SIL).

¹ Type B element: "Complex" element (using micro controllers or programmable logic); for details see 7.4.4.1.3 of IEC 61508-2, ed2, 2010.

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1 Purpose and Scope

This document shall describe the results of the hardware assessment in the form of the Failure Modes, Effects and Diagnostic Analysis carried out on the 2130 Level Switch. From this, failure rates and for each failure mode/category, useful life, and proof test coverage are determined.

The information in this report can be used to evaluate whether an element meets the average Probability of Failure on Demand (PFD_{avg}) requirements and if applicable, the architectural constraints / minimum hardware fault tolerance requirements per IEC 61508 / IEC 61511.

An FMEDA is part of the effort needed to achieve full certification per IEC 61508 or other relevant functional safety standard.

2 Project Management

2.1 *exida*

exida is one of the world's leading accredited Certification Bodies and knowledge companies specializing in automation system safety, availability, and cybersecurity with over 500 person years of cumulative experience in functional safety, alarm management, and cybersecurity. Founded by several of the world's top reliability and safety experts from manufacturers, operators and assessment organizations, *exida* is a global corporation with offices around the world. *exida* offers training, coaching, project-oriented consulting services, safety engineering tools, detailed product assurance and ANSI accredited functional safety and cybersecurity certification. *exida* maintains a comprehensive failure rate and failure mode database on electronic and mechanical equipment and a comprehensive database on solutions to meet safety standards such as IEC 61508.

2.2 Roles of the parties involved

exida most recently modified the hardware assessment in June-2015 and updates are noted in section 7.2. No significant hardware changes have been made since then.

2.3 Standards and literature used

The services delivered by *exida* were performed based on the following standards / literature.

2.4 *exida* **tools used**

[T1] V2.0.1 FMEDAx Tool

2.5 Reference documents

2.5.1 Documentation provided by Rosemount Tank Radar

2.5.2 Documentation generated by *exida*

3 Product Description

The 2130 Level Switch is a smart device used in many different industries for point level sensing applications. It contains self-diagnostics and is programmed to send its output to a specified failure state upon internal detection of a failure.

The 2130 is designed using the tuning fork principle. The 2130 continuously monitors changes in its vibrating fork's natural resonant frequency. When used as a high-level alarm, the liquid rising in the vessel contacts the fork resulting in a reduction of its frequency; this is detected by the electronics which switches the output state to OFF. As a switch the device only supports two valid output conditions defined as the ON and OFF states. Diagnostic annunciation of detectable faults is available via local LED indication and potential transition to the OFF state depending on the type of fault and configured mode of operation. When used as a low-level alarm, the liquid in the tank or pipe drains down past the fork, causing a change of natural frequency that is detected by the electronics and switches the output state.

The device's Mode Switch is used to set the mode of operation for the device. When set to "Dry On" the device is configured for High Level Trip applications and when set to "Wet On" it is configured for Low Level Trip applications.

The 2130 Level Switch is available in different models that support a selection of electrical interfaces. [Table 2](#page-10-1) is an overview of the models in the FMEDA of the 2130 Level Switch.

Table 2 Version Overview

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Each electrical interface has interface specific ON and OFF states defined for the interface. The alarm state is considered to be the OFF state by default, following de-energize to trip safety principles.

[Figure 1](#page-11-0) provides an overview of the 2130 Level Switch and the boundary of the FMEDA.

Figure 1 2130 Level Switch, Parts included in the FMEDA

The 2130 Level Switch is classified as a Type B^2 element according to IEC 61508, having a hardware fault tolerance of 0.

² Type B element: "Complex" element (using micro controllers or programmable logic); for details see 7.4.4.1.3 of IEC 61508-2, ed2, 2010.

4 Failure Modes, Effects, and Diagnostic Analysis

The Failure Modes, Effects, and Diagnostic Analysis was performed based on the documentation in section [2.5.1](#page-7-0) and is documented in section [2.5.2.](#page-8-0)

When the effect of a certain failure mode could not be analyzed theoretically, the failure modes were introduced on component level and the effects of these failure modes were examined on system level, see Fault Injection Test Report [\[D13\].](#page-7-3)

4.1 Failure categories description

In order to judge the failure behavior of the 2130 Level Switch, the following definitions for the failure of the device were considered.

The failure categories listed above expand on the categories listed in IEC 61508 which are only safe and dangerous, both detected and undetected. In IEC 61508, Edition 2010, the No Effect failures cannot contribute to the failure rate of the safety function. Therefore they are not used for the Safe Failure Fraction calculation needed when Route 2_H failure data is not available.

When using the NAMUR current output interface, a Fail High will appear to be a stuck at ON output state and be dangerous undetected unless detected by shorted field wire diagnostic and properly handled by the capability and programming of the logic solver. The Fail Low will appear to be a stuck at the failsafe OFF output state if not detected and handled differently by open circuit line monitoring. Consequently, during a Safety Integrity Level (SIL) verification assessment the Fail High and Fail Low failure categories need to be classified as safe or dangerous, detected or undetected.

The Annunciation failures are provided for those who wish to do reliability modeling more detailed than required by IEC61508. It is assumed that the probability model will correctly account for the Annunciation failures.

4.2 Methodology – FMEDA, failure rates

4.2.1 FMEDA

A FMEDA (Failure Mode Effect and Diagnostic Analysis) is a failure rate prediction technique based on a study of design strength versus operational profile stress. It combines standard FMEA techniques and parts stress analysis with extensions to identify automatic diagnostic techniques, the failure modes relevant to safety instrumented system design, and proof test coverage. It is a technique recommended to generate failure rates for each failure mode category [\[N13\],](#page-6-2) [\[N14\].](#page-6-3)

4.2.2 Failure rates

The accuracy of any FMEDA analysis depends upon the component reliability data as input to the process. Component data from consumer, transportation, military or telephone applications could generate failure rate data unsuitable for the process industries. The component data used by *exida* in this FMEDA is from the Component Reliability Database [\[N2\],](#page-5-4) [\[N3\]](#page-5-5) which was derived using:

- Over 400 billion unit operational hours of process industry field failure data from multiple sources.
- Failure data formulas derived from IEC TR 62380, SN 29500 and industry sources.
- Manufacturer Meetings.
- Component Research.

The rates for the NAMUR current output interface, 8/16 mA current output and relay output versions were chosen to match *exida* Profile 2. See [Appendix A.](#page-30-0) The *exida* profile chosen was judged to be the best fit for the product and application information submitted by Rosemount Tank Radar. It is expected that the actual number of field failures due to random events will be less than the number predicted by these failure rates.

Early life failures (infant mortality) are not included in the failure rate prediction as it is assumed that some level of commission testing is done. End of life failures are not included in the failure rate prediction as useful life is specified.

The failure rates are predicted for a Site Safety Index of SSI=2 [\[N10\],](#page-6-0) [\[N11\]](#page-6-1) as this level of operation is common in the process industries. Failure rate predictions for other SSI levels are included in the exSILentia® tool from exida

The user of these numbers is responsible for determining their applicability to any particular environment. *exida* Environmental Profiles listing expected stress levels can be found in [Appendix](#page-30-0) [A.](#page-30-0) Some industrial plant sites have high levels of stress. Under those conditions the failure rate data is adjusted to a higher value to account for the specific conditions of the plant. *exida* has detailed models available to make customized failure rate predictions. Contact *exida* for assistance.

Accurate plant specific data may be used for this purpose. If a user has data collected from a good proof test reporting system such as *exida* SILStat[™] that indicates higher failure rates, the higher numbers shall be used.

4.3 Assumptions

The following assumptions have been made during the Failure Modes, Effects, and Diagnostic Analysis of the 2130 Level Switch.

- Only a single component failure will fail the entire 2130 Level Switch.
- Failure rates are constant; wear-out mechanisms are not included.
- Propagation of failures is not relevant.
- All components that are not part of the safety function and cannot influence the safety function (feedback immune) are excluded.
- Failures caused by operational errors or maintenance capability are site specific and therefore are not included.
- The stress levels are average for an industrial environment and can be compared to the *exida* Profile 2 with temperature limits within the manufacturer's rating, or Profile 3 for the PNP/PLC and Direct Load versions. Other environmental characteristics are assumed to be within manufacturer's rating.
- Additional fault insertion tests can demonstrate the correctness of the failure effects assumed during the FMEDA and the diagnostic coverage provided by the automatic diagnostics.
- The application program in the logic solver is constructed in such a way that Fail High and Fail Low failures are detected regardless of the effect, safe or dangerous, on the safety function.
- Materials are compatible with process conditions.
- The device is installed per manufacturer's instructions.
- External power supply failure rates are not included.
- Worst-case internal fault detection time is less than 1 hour.
- Relay contacts in the 2130 D version are transient and have over-current protection.
- • The enhanced self-check configuration option is enabled.

4.3.1 User Configuration Restrictions

In addition to basic FMEDA assumptions, the following additional application configuration restrictions were also considered as part of this analysis and must be followed for the results presented in this report to be correct.

- The 2130 Level Switch will be used in the standard de-energize to trip mode of operation.
	- \circ use DRY = On modes of operation for high level detection applications
	- \circ use WET = On modes of operation for low level detection applications
- The 2130 models of 2130 Level Switch will be configured to run in the Enhanced self-check mode of operation when used in WET = On (low level detection) applications.
- The 2130 Level Switch worst case response time shall be considered to be the larger of 10 seconds plus the switch setting for response mode of operation.

4.4 Failure Rate Results

Using reliability data extracted from the *exida* Electrical and Mechanical Component Reliability Handbook the following failure rates resulted from the 2130 Level Switch FMEDA. All failure rates in this section assume a Site Safety Index (SSI) of 2 (good site maintenance practices). See [Appendix C](#page-35-0) for an explanation of SSI of 0 (very poor maintenance practices) through SSI of 4 (ideal maintenance practices).

All failure rates in this section assume a Site Safety Index (SSI) of 2 (good site maintenance practices). See [Appendix C](#page-35-0) for an explanation of SSI of 0 (very poor maintenance practices) through SSI of 4 (ideal maintenance practices).

The failure rates for the 2130 NAMUR (N) model Level Switch with the High Temperature Sensor configured as DRY = On are listed in [Table 3.](#page-16-1)

Table 3 Failure rates 2130 Level Switch, NAMUR (N) - DRY = On

The failure rates for the 2130 NAMUR (N) model Level Switch with the High Temperature Sensor configured as WET = On are listed in [Table 4.](#page-16-2)

Table 4 Failure rates 2130 Level Switch, NAMUR (N) - WET = On

The failure rates for the 2130 Relay (D) model Level Switch using one changeover contact without the FAULT Relay, with the High Temperature Sensor configured as DRY = On are listed in [Table 5.](#page-17-0)

Table 5 Failure rates 2130 Level Switch, Relay (D) - DRY = On

The failure rates for the 2130 Relay (D) model Level Switch using one changeover contact without the Fault Relay, with the High Temperature Sensor configured as WET = On are listed in [Table 6.](#page-17-1)

Table 6 Failure rates 2130 Level Switch, Relay (D) - WET = On

The failure rates for the 2130 Relay (D) model Level Switch with the FAULT Relay, with the High Temperature Sensor configured as \overrightarrow{DRY} = On are listed in [Table 7.](#page-18-0)

The failure rates for the 2130 Relay (D) model Level Switch with the Fault Relay, with the High Temperature Sensor configured as WET = On are listed in [Table 8.](#page-18-1)

The failure rates for the 8/16 mA (M) model Level Switch with the High Temperature Sensor configured as DRY = On are listed in T able 9.

The failure rates for the 2130 8/16 mA (M) model Level Switch with the High Temperature Sensor configured as WET = On are listed in [Table 10.](#page-19-1)

Table 10 Failure rates 2130 Level Switch, 8/16 mA (M) - WET = On

The failure rates for the 2130 PNP/PLC (P) model Point Level Switch with the High Temperature Sensor configured as DRY = On are listed in [Table 11.](#page-20-0)

The failure rates for the 2130 PNP/PLC (P) model Point Level Switch with the High Temperature Sensor configured as WET = On are listed in [Table 12.](#page-20-1)

Table 12 Failure rates 2130 Point Level Switch, PNP/PLC (P) - WET = On

Failure Category	Failure Rate (FIT)		
Fail Safe Undetected		60	
Fail Dangerous Detected		284	
Fail Detected (detected by internal diagnostics)	284		
Fail High (detected by logic solver)	-		
Fail Low (detected by logic solver)	۰		
Fail Dangerous Undetected		54	
No Effect		239	
Annunciation Undetected		8	

The failure rates for the 2130 Direct Load Switching (L) model Point Level Switch with the High Temperature Sensor configured as DRY = On are listed in [Table 13.](#page-21-0)

The failure rates for the 2130 Direct Load Switching (L) model Point Level Switch with the High Temperature Sensor configured as WET = On are listed in [Table 14.](#page-21-1)

[Table 15](#page-22-2) lists the failure rates for the 2130 Level Switch according to IEC 61508. All failure rates in this section assume a Site Safety Index (SSI) of 2 (good site maintenance practices).

Table 15 Failure rates according to IEC 61508, values in FITs

Where:

 λ_{SD} = Fail Safe Detected

 λ_{SU} = Fail Safe Undetected

 λ_{DD} = Fail Dangerous Detected

 λ_{DU} = Fail Dangerous Undetected

 $#$ = No Effect Failures

These failure rates are valid for the useful lifetime of the product, see section [4.6.](#page-24-0)

4.5 Proof Test Coverage

According to section 7.4.5.2 f) of IEC 61508-2 proof tests shall be undertaken to reveal dangerous faults which are undetected by automatic diagnostic tests. This means that it is necessary to specify how dangerous undetected faults which have been noted during the Failure Modes, Effects, and Diagnostic Analysis can be detected during proof testing.

4.5.1 Suggested Full Proof Test

The suggested proof test described in [Table 16](#page-23-1) will detect at least 78% of possible DU failures in the 2130 Level Switch versions listed. See [Table 18](#page-23-2) for a specific model and coverage combination.

³ It is important to realize that the No Effect failures are no longer included in the Safe Undetected failure category according to IEC 61508, ed2, 2010.

Table 16 Suggested Full Proof Test

4.5.2 Suggested Partial Proof Test

The suggested proof test described in [Table 17](#page-23-3) will detect at least 77% of possible DU failures in the 2130 Level Switch versions listed. See [Table 18](#page-23-2) for a specific model and coverage combination.

Table 18 Combinations of Models and DU Coverages.

4.6 Useful Life

The Useful Life of the device predicted by component failure data of 10 years.

4.7 Architecture Constraints

According to IEC 61508-2 the architectural constraints of an element must be determined. This can be done by following the 1 $_H$ approach according to 7.4.4.2 of IEC 61508-2 or the 2 $_H$ approach according to 7.4.4.3 of IEC 61508-2, or the approach according to IEC 61511:2016 which is based on 2_H (see Section [5.2\)](#page-25-0).

The 1_H approach involves calculating the Safe Failure Fraction for the entire element.

The 2_H approach involves assessment of the reliability data for the entire element according to 7.4.4.3.3 of IEC 61508-2.

The failure rate data used for this analysis meets the *exida* criteria for Route 2_H (which is more stringent than IEC 61508-2) (and the diagnostic coverage resulting from the analysis exceeds the required 60% threshold). Therefore, the 2130 Level Switch meets the hardware architectural constraints for up to SIL 2 at HFT=0 (or SIL 3 at HFT=1) when the listed failure rates are used.

The architectural constraint type for the 2130 Level Switch is B. The hardware fault tolerance of the device is 0. The SIS designer is responsible for meeting other requirements of applicable standards for any given SIL.

5 Using the FMEDA Results

The following section(s) describe how to apply the results of the FMEDA.

5.1 PFDavg calculation

Using the failure rate data displayed in section [4.4,](#page-16-0) and the failure rate data for the associated element devices, an average the Probability of Failure on Demand (PFD_{avg}) calculation can be performed for the element.

Probability of Failure on Demand (PFD_{avq}) calculation uses several parameters, many of which are determined by the particular application and the operational policies of each site. Some parameters are product specific and the responsibility of the manufacturer. Those manufacturer specific parameters are given in this third party report.

Probability of Failure on Demand (PFD_{avg}) calculation is the responsibility of the owner/operator of a process and is often delegated to the SIF designer. Product manufacturers can only provide a PFD_{avg} by making many assumptions about the application and operational policies of a site. Therefore use of these numbers requires complete knowledge of the assumptions and a match with the actual application and site.

Probability of Failure on Demand (PFD_{avg}) calculation is best accomplished with *exida's* exSILentia tool. See [Appendix B](#page-31-0) for a complete description of how to determine the Safety Integrity Level for an element. The mission time used for the calculation depends on the PFD_{avg} target and the useful life of the product. The failure rates and the proof test coverage for the element are required to perform the PFD_{avg} calculation. The proof test coverages for the suggested proof tests are listed in [Table 16](#page-23-1) and [Table 17.](#page-23-3)

5.2 *exida* **Route 2H Criteria**

IEC 61508, ed2, 2010 describes the Route 2_H alternative to Route 1 $_H$ architectural constraints. The standard states:

"based on data collected in accordance with published standards (e.g., IEC 60300-3-2: or ISO 14224); and, be evaluated according to

- the amount of field feedback; and
- the exercise of **expert judgment**; and
- when needed, the undertaking of specific tests,

in order to estimate the average and the uncertainty level (e.g., the 90% confidence interval or the probability distribution) of each reliability parameter (e.g., failure rate) used in the calculations."

exida has interpreted this to mean not just a simple 90% confidence level in the uncertainty analysis, but a high confidence level in the entire data collection process. As IEC 61508, ed2, 2010 does not give detailed criteria for Route 2_H , *exida* has established the following:

1. field unit operational hours of 10,000,000 per each component or known common usage of the component for over ten years in at least 10 units; and

2. operational hours are counted only when the data collection process has been audited for correctness and completeness; and

3. failure definitions are realistic without data censoring of failures with both a systematic and random failure cause [\[N9\];](#page-6-4) and

4. every component used in an FMEDA meets the above criteria.

This set of requirements is chosen to assure high integrity failure data suitable for safety integrity verification. [\[N12\]](#page-6-5)

6 Terms and Definitions

7 Status of the Document

7.1 Liability

exida prepares FMEDA reports based on methods advocated in engineering literature and International technical reports. Failure rates are obtained from field failure studies and other sources. *exida* accepts no liability whatsoever for the use of these numbers or for the correctness of the standards on which the general calculation methods are based.

Due to future potential changes in the standards, product design changes, best available information and best practices, the current FMEDA results presented in this report may not be fully consistent with results that would be presented for the identical model number product at some future time.

Most products also tend to undergo incremental changes over time. If an *exida* FMEDA has not been updated within the last three years, contact the product vendor to verify the current validity of the results.

7.2 Version History

Reviewer: Rudy Chalupa, *exida*, 7 March 2024

Status: Released, 7 March 2024

7.3 Future enhancements

At request of client.

7.4 Release Signatures

Valon Motto

Valerie Motto, CFSP, Safety Engineer

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Appendix A *exida* **Environmental Profiles**

Table 19 *exida* **Environmental Profiles**

⁴ Humidity rating per IEC 60068-2-3

- ⁶ Vibration rating per IEC 60770-1
- ⁷ Chemical Corrosion rating per ISA 71.04
- ⁸ Surge rating per IEC 61000-4-5
- ⁹ EMI Susceptibility rating per IEC 6100-4-3

⁵ Shock rating per IEC 60068-2-6

¹⁰ ESD (Air) rating per IEC 61000-4-2

Appendix B Determining Safety Integrity Level

The information in this appendix is intended to provide the method of determining the Safety Integrity Level (SIL) of a Safety Instrumented Function (SIF). The numbers used in the examples are not for the product described in this report.

Three things must be checked when verifying that a given Safety Instrumented Function (SIF) design meets a Safety Integrity Level (SIL) [\[N5\]](#page-5-6) and [\[N7\].](#page-5-7)

These are:

A. Systematic Capability or Prior Use Justification for each device meets the SIL level of the SIF;

B. Architecture Constraints (minimum redundancy requirements) are met; and

C. a PFD_{avg} calculation result is within the range of numbers given for the SIL level.

A. Systematic Capability (SC) is defined in IEC61508:2010. The SC rating is a measure of design quality based upon the methods and techniques used to design and development a product. All devices in a SIF must have a SC rating equal or greater than the SIL level of the SIF. For example, a SIF is designed to meet SIL 3 with three pressure transmitters in a 2oo3 voting scheme. The transmitters have an SC2 rating. The design does not meet SIL 3. Alternatively, IEC 61511 allows the end user to perform a "Prior Use" justification. The end user evaluates the equipment to a given SIL level, documents the evaluation and takes responsibility for the justification.

B. Architecture constraints require certain minimum levels of redundancy. Different tables show different levels of redundancy for each SIL level. A table is chosen, and redundancy is incorporated into the design [\[N8\].](#page-6-6)

C. Probability of Failure on Demand (PFD_{avg}) calculation uses several parameters, many of which are determined by the particular application and the operational policies of each site. Some parameters are product specific and the responsibility of the manufacturer. Those manufacturer specific parameters are given in this third party report.

A Probability of Failure on Demand (PFD_{avg}) calculation must be done based on a number of variables including:

1. Failure rates of each product in the design including failure modes and any diagnostic coverage from automatic diagnostics (an attribute of the product given by this FMEDA report);

- 2. Redundancy of devices including common cause failures (an attribute of the SIF design);
- 3. Proof Test Intervals (assignable by end user practices);
- 4. Mean Time to Restore (an attribute of end user practices);

5. Proof Test Effectiveness; (an attribute of the proof test method used by the end user with an example given by this report);

- 6. Mission Time (an attribute of end user practices);
- 7. Proof Testing with process online or shutdown (an attribute of end user practices);
- 8. Proof Test Duration (an attribute of end user practices); and
- 9. Operational/Maintenance Capability (an attribute of end user practices).

The product manufacturer is responsible for the first variable. Most manufacturers use the *exida* FMEDA technique which is based on over 100 billion hours of field failure data in the process industries to predict these failure rates as seen in this report. A system designer chooses the second variable. All other variables are the responsibility of the end user site. The exSILentia® SILVer™ software considers all these variables and provides an effective means to calculate PFD_{ava} for any given set of variables.

Simplified equations often account for only for first three variables. The equations published in IEC 61508-6, Annex B.3.2 [\[N1\]](#page-5-8) cover only the first four variables. IEC61508-6 is only an informative portion of the standard and as such gives only concepts, examples and guidance based on the idealistic assumptions stated. These assumptions often result in optimistic $\overline{PFD}_{\text{avg}}$ calculations and have indicated SIL levels higher than reality. Therefore idealistic equations should not be used for actual SIF design verification.

All the variables listed above are important. As an example consider a high level protection SIF. The proposed design has a single SIL 3 certified level transmitter, a SIL 3 certified safety logic solver, and a single remote actuated valve consisting of a certified solenoid valve, certified scotch yoke actuator and a certified ball valve. Note that the numbers chosen are only an example and not the product described in this report.

Using exSILentia with the following variables selected to represent results from simplified equations:

- Mission Time $= 5$ years
- Proof Test Interval = 1 year for the sensor and final element, 5 years for the logic solver
- Proof Test Coverage = 100% (ideal and unrealistic but commonly assumed)
- Proof Test done with process offline

This results in a PFD_{avg} of 6.82E-03 which meets SIL 2 with a risk reduction factor of 147. The subsystem PFD_{avg} contributions are Sensor PFD_{avg} = 5.55E-04, Logic Solver PFD_{avg} = 9.55E-06, and Final Element $\overline{PP}_{avg} = 6.26E-03$. See [Figure 2.](#page-32-0)

Figure 2: exSILentia results for idealistic variables.

If the Proof Test Interval for the sensor and final element is increased in one year increments, the results are shown in [Figure 3.](#page-33-7)

Figure 3 PFDavg versus Proof Test Interval.

If a set of realistic variables for the same SIF are entered into the exSILentia software including:

- Mission Time = 25 years
- Proof Test Interval = 1 year for the sensor and final element, 5 years for the logic solver
- Proof Test Coverage = 90% for the sensor and 70% for the final element
- Proof Test Duration = 2 hours with process online.
- $MTTR = 48$ hours
- Maintenance Capability = Medium for sensor and final element, Good for logic solver

with all other variables remaining the same, the PFD_{avg} for the SIF equals 5.76E-02 which barely meets SIL 1 with a risk reduction factor 17. The subsystem PFD_{avg} contributions are Sensor PFD_{avg} $= 2.77E-03$, Logic Solver PFD_{avg} = 1.14E-05, and Final Element PFD_{avg} = 5.49E-02 [\(Figure 4\)](#page-34-0).

Navigation λ Final Element Group1 Level Trip 1001 1001 Logic Solver 1001 1001								
Safety Instrumented Function Results $\hat{}$								
PFDavg Contribution	Achieved Safety Integrity Level			$\mathbf{1}$				
Sensors Logic Solver Final Elements	Safety Integrity Level (PFDavg)			$\mathbf{1}$				
	Safety Integrity Level (Architectural Constraints)			2				
	Safety Integrity Level (Systematic Capability)			2				
	Average Probability of Failure on Demand (PFDavg)				5.76E-02			
	Risk Reduction Factor (RRF)				17			
MTTFS Contribution	Mean Time to Failure Spurious (MTTFS) [years]			137.49				
Sensors Logic Solver Final Elements		PFDavg	MTTFS [years]	SIL PFDavg	SIL Limits			
					Arch. Const.	Sys. Cap.		
	Sensor Part	2.77E-03	622		2	2		
	Logic Solver Part	1.14E-05	1057.57	1	3	3		
	Final Element Part	5.49E-02	211.87		2	3		

Figure 4: exSILentia results with realistic variables

It is clear that PFD_{avg} results can change an entire SIL level or more when all critical variables are not used.

Appendix C Site Safety Index

Numerous field failure studies have shown that the failure rate for a specific device (same Manufacturer and Model number) will vary from site to site. The Site Safety Index (SSI) was created to account for these failure rates differences as well as other variables. The information in this appendix is intended to provide an overview of the Site Safety Index (SSI) model used by *exida* to compensate for site variables including device failure rates.

C.1 Site Safety Index Profiles

The SSI is a number from 0 – 4 which is an indication of the level of site activities and practices that contribute to the safety performance of SIFs on the site. [Table 20](#page-35-2) details the interpretation of each SSI level. Note that the levels mirror the levels of SIL assignment, and that SSI 4 implies that all requirements of IEC 61508 and IEC 61511 are met at the site and therefore there is no degradation in safety performance due to any end-user activities or practices, i.e., that the product inherent safety performance is achieved.

Several factors have been identified thus far which impact the Site Safety Index (SSI). These include the quality of:

Commission Test Safety Validation Test Proof Test Procedures Proof Test Documentation Failure Diagnostic and Repair Procedures Device Useful Life Tracking and Replacement Process SIS Modification Procedures SIS Decommissioning Procedures and others

Table 20 *exida* **Site Safety Index Profiles**

